

Search Notes

Application/Control No.

09/720,720

Examiner

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Applicant(s)/Patent under
Reexamination

SPITZ ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	63	11/15/2006	BT
216	79	11/15/2006	BT
438	80	11/15/2006	BT
438	719	11/15/2006	BT

INTERFERENCE SEARCHED

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216	63	11/15/2006	BT
216	79	11/15/2006	BT
216	80	11/15/2006	BT
438/719		11/15/2006	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR